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Table of Contents

Message from the Chairs	vii
Committees.....	ix
Sponsors and Supporters.....	xi

Fault Location

FLAVS: A Fault Localization Add-In for Visual Studio	1
<i>Nan Wang, Zheng Zheng, Zhenyu Zhang, Cheng Chen — Beihang University, China; Chinese Academy of Sciences, China</i>	
The Importance of Being Positive in Causal Statistical Fault Localization: Important Properties of Baah et al.'s CSFL Regression Model	7
<i>Zhuofu Bai, Shih-Feng Sun, Andy Podgurski — Case Western Reserve University, USA</i>	
Evaluating Bug Finders—Test and Measurement of Static Code Analyzers	14
<i>Aurelien Delaitre, Bertrand Stivalet, Elizabeth Fong, Vadim Okun — NIST, USA; West Virginia University, USA</i>	
Cross-Technology, Cross-Layer Defect Detection in IT Systems—Challenges and Achievements	21
<i>Philippe-Emmanuel Douziech, Bill Curtis — CAST Research Lab, Germany; CAST Research Lab, USA</i>	

Environment and Failures

The Role of Environmental Assumptions in Failures of DNA Nanosystems	27
<i>Thein Tun, Robyn Lutz, Brian Nakayama, Yijun Yu, Divita Mathur, Bashar Nuseibeh — The Open University, UK; Iowa State University, USA; Lero, Ireland</i>	
Emulating Environment-Dependent Software Faults.....	34
<i>Roberto Pietrantuono, Stefano Russo, Kishor Trivedi — University of Naples Federico II, Italy; Duke University, USA</i>	
Towards Classification of Concurrency Bugs Based on Observable Properties	41
<i>Sara Abbaspour Asadollah, Hans Hansson, Daniel Sundmark, Sigrid Eldh — Malardalen University, Sweden; Ericsson AB, Sweden</i>	

Defect Analysis, Verification, and Modelling

Modeling and Verification of Zone Controller: The SCADE Experience in China's Railway Systems	48
<i>Jie Qian, Jing Liu, Xiang Chen, Junfeng Sun — East China Normal University, China; CASCO Signal Ltd., China</i>	
Defect Analysis over Multiple Release Versions of a Semiconductor Software System	55
<i>Eric Abuta, Jeff Tian — Verity Instruments, USA; Southern Methodist University, USA</i>	
An Imperfect Software Debugging Model Based on Stochastic Differential Equation.....	62
<i>Jinyong Wang, Zhibo Wu, Yanjun Shu, Zhan Zhang — Harbin Institute of Technology, China</i>	
Crying Wolf and Meaning It: Reducing False Alarms in Monitoring of Sporadic Operations through POD-Monitor	69
<i>Xiwei Xu, Liming Zhu, Min Fu, Daniel Sun, An Binh Tran, Paul Rimba, Sri Dwarakanathan, Len Bass — NICTA, Australia</i>	
Author Index	76